

**Search Notes**

Application/Control No.

10/527,760

Examiner

James A. Dudek

Applicant(s)/Patent under  
Reexamination

MIYASHITA ET AL.

Art Unit

2871

**SEARCHED**

Class	Subclass	Date	Examiner
349	73-74	10/10/2006	JAD
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**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR